

**Search Notes**

Application/Control No.

10/686,117

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

SUGAYA ET AL.

Art Unit

2831

**SEARCHED**

Class	Subclass	Date	Examiner
174	72A	2/18/2005	LEE
↓	100		
↓	117F		
439	404		
↓	395		
	443		
	405		
↓	67		
↓	422		
174	as above	6/22/2005	LEE
439	11	10	11

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
174	as above	2/17/2005	LEE
439	as above	2/17/2005	Lee

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
N. Abrams	2/17/2005	LEE
East text search attached	2/18/2005	LEE